

Product Description and Specifications

The HP E2910A PCI Exerciser

Technical Data



With in-system adapter for test at any PCI slot

Key functions

- generate all types of PCI transaction and protocol variations from 0 to 33 MHz
- continuously monitor for protocol violations
- capture and disassemble traffic for multi-level analysis via integrated logic analyzer
- replay and edit captured PCI transactions
- build and run suites of tests automatically
- test PCI protocol compliance



With card adapter

- 3 Slots
- PCI arbiter

Accelerate development of dependable products

The HP E2910A PCI bus exerciser provides you with a powerful tool to accelerate the development of PCI devices and systems significantly and ensure exhaustive verification at the earliest opportunity. Together with a PC running MS Windows 3.1 and a Hewlett-Packard 16500B with HP 16550/4/5/6A logic analyzer for data capture, the HP E2910A brings sophisticated control and analysis capabilities to the PCI bus. From bring-up and debug of individual devices through to integration and troubleshooting in-system, use this independent, controllable agent on the bus to:

- emulate missing device traffic for concurrent development
- generate corner-cases and exceptions within the protocol to verify thoroughly
- record, replay and modify real traffic to reproduce critical cases and isolate the root cause of real problems faster
- identify the "guilty party" fast when anomalies occur
- automate functional and compliance testing to reduce retest time following silicon revisions

Product summary

Bus exerciser card

- generates user-defined transactions as master or target under sequencer control
- detects bus conditions using a pattern recognizor for triggering and branching the test sequencer
- continuously monitors a defined set of protocol rules
- generates sideband signals synchronized to bus transactions



Test sequencer card

- plugs into ISA slot in host PC to control bus exerciser with trigger or branch on event
- provides external trigger input/ output for cross-triggering with logic analyzer

Windows user interface provides

- intuitive set-up and control
- PCI bus transaction description language for defining master and target traffic with complete control
- bus traffic analysis at multiple levels in data lister windows using data from logic analyzer

- automatic comparison of data and protocol behavior with expected data and behavior
- record and replay of bus traffic at transaction level, including wait states

Windows test executive provides

- building and automated sequencing of test suites
- operator configuration of individual test parameters

Customizable compliance test suite

• tests to check PCI protocol compliance

User interface

MS Windows based

The HP E2910A software runs under Windows, fitting seamlessly into the working environment on your PC.

Data-flow oriented

The user interface is oriented around the test-data flow, from sequence and bus exerciser set-up through to captured traffic analysis, making it intuitive and quick to learn and operate. Click on the system block diagram to set-up each part of the system.

ASCII format for data interchange

All set-up and data files are stored in ASCII format for conversion to or from other formats, or processing in other applications. You can easily use custom programs or applications such as spreadsheets to manipulate the files.

On-line help

Comprehensive on-line help is available at all times, covering all aspects of operating the bus exerciser and shortening the learning curve.

Pattern editor

Set up logical combinations of signals which the pattern recognizor should detect. The patterns can then be used in the test sequencer to make branching decisions.

Sequence editor

Define states, actions and branching conditions to set up a transaction sequence based on your defined transaction blocks and pattern events.







	Sequence Editor [RVV.SEQ]	-
<u>File Edit Check He</u>	elp	_
	saction write best, wait for completion any video and start transaction try_burst	1
	//State 1 label (Optional) //Start transaction write_best and goto next state	
repeat nop	//State 2 label (Optional) //Repeat nop (do nothing) //until ready signal from exerciser //indicates completion of write_best	
if (video) try_burst else	<pre>//State 3 label (Optional) //If pattern video occurs // start transaction try_burst and goto next state //Else // return to this same state</pre>	
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Transaction editor

Use the transaction editor to set up labeled blocks of one or more master and/or target transactions using the PCI bus transaction description language. Each block can then be called from the test sequencer. The PCI bus transaction description language (BTDL) gives you complete control over the protocol behavior of the exerciser.

Phase commands

Use the PCI BTDL to set up transactions on a per phase basis as master or target.

Transaction phase	MASTER Command	TARGET COMMAND
Request Address Address step Data Data step Last data phase Dual address	m_req m_addr m_addr_step m_data m_data_step m_last m_dual_addr	t_data t_data_step

Parameters for protocol control

Within each phase command, use command parameters to control the protocol behavior of the exerciser as master or target.

Attribute	Action
ack64	Assert ACK64# in data phase
addr= <value></value>	AD[31::0] in address phase
hi_addr= <value></value>	AD[64::32] in Dual Address
byten= <value></value>	C/BE[7::0] in data phase
cmd= <value></value>	C/BE[7::0] in address phase
data= <value></value>	AD[31::0] in data phase
hi_data= <value></value>	AD[64::32] in data phase
interrupt(ad)	Assert interrupt line(s)
lock	Exclusive access in address
	phase
marker= <string></string>	Mark phase to find in lister
no_req	Deassert REQ# in data phase
perr	Assert PERR#
req64	Assert REQ64# in address
	phase
serr	Assert SERR#
side0, side1,side7	Assert sideband signal
term = retry	Terminate transaction in
disconnect	target data phase
abort	
try_back	Try fast back-to-back in
	address phase
wait = <value></value>	Force wait states in data
	phase
wr_par	Assert wrong PAR#
wr_par64	Assert wrong PAR64#

Transaction Editor [TED.BCY] <u>F</u>ile <u>E</u>dit <u>C</u>heck <u>S</u>earch <u>H</u>elp #define TARGET a000000\h //Test target's burst capabilities //Expect target to accept a burst memory write of 4 DWORD with fast or //medium address decoding, 1-0-0-0 or 0-0-0-0 wait states. burst write: m addr(addr = TARGET, cmd = m write, exp decode = fast| medium); m_data(data = 01010101\h, exp_wait = 0::1, exp_term = no); //Expect target to accept a burst memory read of 4 DWORD with fast or //medium address decoding, 4-0-0-0, 3-0-0-0, 2-0-0-0, 1-0-0-0 or //0-0-0-0 wait states and check expected data burst_read: m_addr(addr = TARGET, cmd = m_read, exp_decode = fast| medium); म +

Parameters for evaluating test results

Command parameters also let you define the expected behavior of devices under test during each phase of transactions. Define expected data values or protocol behavior to be automatically checked when the captured bus traffic is uploaded and analyzed.

Attribute	Expect
exp_ack64 = id	yes/no//dont_care
exp_addr= <value></value>	AD[31::0] (or implied in burst)
exp_hi_addr=	
<value></value>	AD[63::32] (or implied in burst)
exp_backtoback =id	yes/no/dont_care
exp_burst = id	first, middle , last or any phase
exp_byten=	C/BE[7::0] of data phase
<value></value>	
exp_cmd= <value></value>	C/BE[7::0] in address phase of
	current transfer
exp_decode = id	fast, medium, slow,
	subtractive or none
exp_data=	AD[31::0] in data phase
<value></value>	
exp_hi_data=	AD[64::32] in data phase
<value></value>	
exp_int = id	inta, intb, intc or intd
exp_lock = id	locked access
	yes/no/dont_care
exp_perr = id	yes/no/ don't care
exp_prot_err = error	
exp_req64 = id	yes/no/don't care
exp_serr	yes/no/don't care
exp_side = id	side1, side2., side 3, side4
exp_term =	Target termination
	retry, disconnecta b c,
	abort, accept, any
exp_toreach = id	Phase reached
	yes/no/dont_care
exp_wait = <exp></exp>	Number or range of waits
exp_wr_par = id	yes/no/dont_care
exp_wr_par64=id	yes/no/dont_care

Protocol violations

The exerciser can generate violations such as:

- reserved commands
- illegal number of wait states
- invalid BE/AD[1:0] combinations
- undefined special cycles

To prevent bus contention, signalling protocol cannot be violated.

Macro expansion

Use the extensive macro processing capabilities of the editors to

- simplify the creation of long or complex transactions by generating them algorithmically
- create random tests
- import test parameter data from data files

The macro commands and functions can be used in any of the editors and are expanded at compilation time before the test is carried out.

Macro functions

Command	Description
EOF (handle, remaining)	Returns true if less than remaining items in file
OPEN (name, delimits)	Opens file and returns handle
RAND (min, max)	Returns random integer between specified limits
READ (handle, step)	Returns next integer from file and increments pointer

Macro commands

Command	Description
#CALC	See #VAR
#CLOSE	Close a file or all files
#DEFINE or	Define and evaluate new
#REDEFINE	symbol
#DO , #TIMES	Expand/execute a specified
	number of times
#ERROR	Generate an error message
#FOR, #TO, #STEP,	Expand/execute a specified
#DO	number of times, using a
	stepped index
#IF ,#ELSE	Expand/execute on
	conditions
#IFDEF , IFNDEF #ELSE	Expand/execute if symbol
	defined/no defined
#INCLUDE	Include another filename
#MACRO	Define macro
#SEED	Seed or reseed the random
	number generator
#REPEAT #UNTIL	Repeat expansion/execution
	until a condition occurs
#UNDEFINE	Undefine a symbol for reuse
#VAR	Evaluate an expression and
	assign to symbol
#WHILE #DO	Expand/execute while a
	condition is true



m last(data = FBFFFFC\h, wait = 04\h); m addr(addr = FE030440\h, cmd = m write);

Data listers for traffic analysis

Use the hierarchical data listers to quickly and easily analyze up to 4k of bus state data captured by the logic analyzer. (Use the logic analyzer user interface to pre-filter the data, and for timing analysis). Note that the data listers accept data from state or timing mode.

Bus cycle lister: disassembles the captured data to provide a complete clock-based listing of PCI cycles. Detected protocol violations are clearly indicated. If you define expected data values or protocol behavior in the bus transaction editor, the actual data transfers and protocol are checked and any unexpected results reported.

Bus transaction lister: further disassembles the data to provide a per transaction overview - for example transaction type, address and data content.

Configuration lister: decodes configuration transactions with additional information, interpreting the contents of the configuration data.

Lister correlation

Highlight a section of bus traffic in any lister and it is automatically also marked in the other listers, and in the source bus transaction editor (if the HP E2910A participated in the transaction). The logic analyzer markers can also be set to indicate the corresponding traffic in the waveform or listing displays.





Configuration Lister
<u>Eile C</u> olumns <u>A</u> nalyzer <u>S</u> earch <u>H</u> elp
20: 0 Confiq Read Status + Command 04000000 DEVSEL Timing slow, Not Fast Back-to-Back capable
UDF not supported, Not 66 MHz capable, Fast Back-to-Back not allowed, SERR# driver disabled, Addres
stepping not possible, Ignore parity error, VGA palette snooping not possible, Mem write and
invalidate disabled, Iqnore Special Cycles, Bus Master disabled, Don't respond to mem space
accesses, Don't respond to I/O space accesses,
24: 0 Config Read Class Code + Revision ID 06000000 Bridge Device, HOST bridge; Revision ID 0
28: 0 Config Read BIST + Header Type + Latency Timer + Cache Line Size 00000000 not BIST
capable, completion code 0h; single function device, Header Type 0; latency timer disabled; cache
support disabled;
32: 0 Config Read Base Address Register #0 00000000 unused
36: 0 Config Read Base Address Register #1 00000000 unused
40: 0 Config Read Base Address Register #2 00000000 unused
44: 0 Config Read Base Address Register #3 00000000 unused
48: 0 Config Read Base Address Register #4 00000000 unused
+



Record & replay

Captured bus traffic can be moved from the bus transaction lister to the bus transaction editor for deterministic replay by the exerciser. The captured transactions are converted to the PCI bus transaction language, including recorded wait states, and can be edited as required.

Message log window

The message log window summarizes the results of a test. It lists sequentially all transaction markers and any associated error states of any type from the bus cycle lister, followed by a summary of the total number of protocol violations, data errors and expected protocol behavior errors.

Performance analysis

Real-time performance

System performance is a crucial specification, and comparing long term bus-performance measurements under real operating conditions can help you

- · identify bottlenecks
- optimize system settings
- compare system platforms and devices

In passive observer mode, two 64 bit hardware counters are able to count defined bus events in real time to provide cumulative performance statistics over long periods of time.

The counters are controlled via the pattern recognizor and you can define three control patterns for each counter

- enable counter
- count
- disable counter

This allows you to count events within a specified window. For example, you can enable a counter on an address phase to a particular address range, count all data transfer phases and disable the counter on an idle phase in order to count all data transfers to the target address range. By using the second counter to count the wait states, you can measure the transfer efficiency, in terms of wait states per data transfer, to that target.

Perfo	rmance	
PCI Bus Performance	;	
	4 47000	
Counter #1 :	147666	
Counter #2 :	1709183	
Ratio #1 / #2:	0.086396	
Close		
CIUSE		

Pattern Editor [PERFORM.PAT]	-
<u>F</u> ile <u>E</u> dit <u>C</u> heck <u>S</u> earch <u>H</u> elp	
#define TARGET_ADDR_PATTERN (!FRAME && (AD	31:0] == axxxxxxx\h))
//	
<pre>// Measurement: Bus efficiency of a particu</pre>	.ar target.
//	
// # of data phases to t	is target
// Formula:	
// # of clocks used in transac	ions to this target
	t- pl
COUNTER COUNT1 = !IRDY && !TRDY; //D	
COUNTER ENABLE1 = TARGET_ADDR_PATTERN; //E	able on Address
COUNTER DISABLE1 = FRAME && IRDY; //D	sable on Idle
COUNTER COUNT2 = 1; //C	unt every clock
COUNTER ENABLE2 = TARGET ADDR PATTERN; //E	-
COUNTER DISABLE2 = FRAME $\overline{\&}$ IRDY; //D	sable on Idle
+	

Automated test environment

Automated testing

Use the automatic testing capabilities of the HP E2910A to run suites of tests automatically, and reduce the time necessary for retesting of new silicon revisions or system configurations. A test suite is supplied to help test PCI protocol compliance of a device. The suite requires customization for a particular implementation under test (IUT), and can be expanded to include your own tests. The automated test environment consists of three elements:

- · test executive shell
- test suite for PCI protocol compliance
- · DOS test shell

Test executive shell (TES)

With the test executive shell (TES) you can set up, configure and run sequences of HP E2910A tests. New tests are developed and debugged using the normal HP E2910A user interface, then built into a test suite using the TES. When running a test suite under the TES you can:

- configure test suite parameters, such as IUT memory address, HP E2910A addresses, and IUT/system capabilities
- configure test sequence and branching conditions, such as stop/pause/repeat/skip on test pass or fail
- generate a test report file with test result summary, test log and test configuration record

The TES judges a test as failed if any protocol, expected data or expected IUT behavior errors occur during the test. When a test fails, you use the HP E2910A user interface to load and re-run the test and investigate the root cause of the failure in detail with the analysis listers.





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Ē	<u>I</u> nfo	/Ctrl		Test Sequence	Parameters		Pre/Post Run Pat <u>h</u> s
Γ					Test Sequer	nce —	
		Label	Do	Test Name	Parm Instance		
	1 2			init t1 01mem	default default		suites\tests\init.bst suites\tests\t1_01mem.bst
	3			t1 01io	default		suites/tests/t1_01io.bst
	4			t1_01con	default		suites\tests\t1_01con.bst
	5			t1_02mem	default	_	suites\tests\t1_02mem.bst
	6			t1_02io	default	_	suites\tests\t1_02io.bst
	7			t1_02con	default default		suites\tests\t1_02con.bst suites\tests\t1_03mem.bst
	8			t1_03mem t1_03io	default default		suites\tests\t1_U3mem.bst suites\tests\t1_03io.bst
	10			t1_03con	default		suites/tests/t1_03con.bst +
	<u>+</u>		_				+
		Bu	<u>n</u> T	est <u>E</u> dit Te	st <u>V</u>	<u>fiew</u> Bl	EST
Г			Te	st branching options —		٢	Editing
	1 2 3 4	Condition		Action Action D	DI Units +		q <u>i</u> from ngo stolog
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Compliance test suite

The test suite provides more than forty HP E2910A tests to check most items in the PCI SIG component protocol checklist for master and target devices.

1.1 Device speed: Memory, I/O, configuration 1.2 Target abort: Memory, I/O, configuration 1.3 Target retry : Memory, I/O, configuration 1.4 Single data disconnect: Memory, I/O, configuration 1.5 Multi-data phase target abort: Memory, dual address, I/O, configuration, MRM, MRL, MW&I 1.6 Multi-data phase retry: Memory, I/O, configuration, MRN MRL, MW&I 1.7 Multi-data phase disconnect: memory, I/O, configuration, MRM, MRL, MW&I 1.8 Multi-data phase & TRDY#: memory, dual address, I/O, Configuration, MRM, MRL, MW&I 1.8 Multi-data phase & TRDY#: memory, dual address, I/O, Configuration, MRM, MRL, MW&I 1.9 Data parity error single data: memory, I/O, configuration 1.10 Data parity error multi-data phase Memory, dual address, configuration, MRM, MRL, MW&I 1.11 Bus master timeout: MW&I 1.12 Target lock:	
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1.11 Bus master timeout: MW&I	
2.2 Target reception of special cycle	
2.3 Target detection of A/D parity err	or
address, data	
2.4 Target reception of I/O with lega	
and illegal byte enables	
2.5 Target ignores reserved comman	ds
2.6 Target receives configuration cyc	
2.7 Target receives I/O waith A/D par	
errors	
2.8 Target gets configuration cycles	
with A/D parity errors	
2.9 Target receives memory cycles	
2.10 Target gets memory cycles with A	₹/D
parity errors	
2.11 Target gets fast back-to-back cyc	
2.12 Target performs exlusive access:	
accepts lock, releases lock	
2.13 Target gets cycles with IRDY data	cles
stepping (waits)	cles

For 1.x scenarios, the HP E2910A behaves as target to the IUT's master. For 2.x scenarios, the HP E2910A generates traffic as master to the IUT's target. The following cases within the scenarios are not covered by the suite:

- fast/subtractive decode as target of memory, memory read multiple, memory read line and memory read and invalidate
- fast/subtractive/slow decode as target of configuration cycles
- tests requiring control over the arbiter
- multiple master tests
- interrupt tests

Each HP E2910A test contains comments explaining which test items are addressed by the test, as well as markers throughout the file which indicate the individual test items and allow you to correlate between the test report, the PCI compliance checklist and the test source file.

Using the compliance suite

To configure the test suite parameters you need to know your IUT and IUT system. For example, you need to set up parameters identifing the types of PCI capabilities supported by the IUT, and parameters indicating free system memory and PCI address spaces for the HP E2910A and DTS to use. Once configured, test suites can be run without detailed knowledge of PCI, HP E2910A syntax or the IUT.

The compliance tests require that the DTS is running on the system containing the IUT in order to control the IUT. The DTS already includes test functions for host bridge IUTs, but you may need to develop DTS functions for a peripheral IUT. Refer to the DOS test shell description.

To debug and identify the root cause of a failed test, use the HP E2910A user interface to correlate the traffic in the analysis listers with the HP E2910A test, and to rerun the test. Each test contains comments to identify the test cases covered and how it is checked, but you need to be familiar with the HP E2910A bus transaction language, the PCI protocol and checklist and your IUT specification to debug a problem effectively.



DOS test shell (DTS)

The DOS test shell (DTS) runs under DOS on the system containing the implementation Under test (IUT). An HP E2910A test controls the DTS through system memory, using a predefined set of handshaking macros. This allows an HP E2910A test to call associated DTS functions by library number and function number. DTS functions are used to set-up and control the IUT from the CPU in the IUT system. For example, to make the IUT generate master transactions for the 1.x scenarios, or to initialize the IUT if this is not practical using the HP E2910A.

The DTS includes a host bridge function library which is ready to use with the compliance test suite to test host bridge devices. These functions make use of PCI BIOS calls to control the host bridge.

Function	Description
	2000.12.000
1	Nop
5	Initialize IUT for test
10	Clear IUT status register
20	Read IUT config register
30	Perform memory write
40	Perform memory read
50	Perform I/O read
60	Peform I/O write
70	Perform config read
80	Perform config write
90	Perform config read to empty slot
91	Perform config write to empty slot
92	Perform memory read multiple
93	Perform memory read line
94	Perform memory write & invalidate
95	Perform dual address memory write
96	Perform dual address memory read
100	Locate HP E2910A
141	Set PCI register bit
142	Save IUT command register
143	Restore IUT command register
150	End of test

To test peripheral devices you have to add a new library of DTS functions which force your IUT to perform the PCI master functions (30 to 96) required for 1.x scenarios, perhaps using an existing driver. The number of functions you need to create depends on the PCI master capabilities of your IUT. No functions are required for the 2.x scenarios (IUT target). To program new DTS routines for an IUT you need register-level knowledge of the IUT, or its driver and Microsoft Visual C++.

The DTS requires the IUT system to be IBM PC_AT compatible with 386 or later CPU, DOS 5.0 or later, at least 512k RAM, PCI BIOS and one free PCI slot for the HP E2910A with in-system adapter.

The entire DTS source code (C++ and assembler) is supplied, and may be used as a template for developing new functions or for porting to other platforms.

Hardware Overview

Test sequencer card



The test sequencer card plugs into an ISA-compatible slot in the controlling PC. Running at up to 33 MHz, the test sequencer state machine allows you to define complex sequences of transactions with triggering/branching on system events detected by the pattern recognizor or logic analyzer. This helps you reproduce problems which occur after a complex sequence of system events. The test sequence is defined as a series of test states during which actions, and the branching conditions for branching between states occur.

Number of states

60 states maximum.

Branching inputs

Maximum of seven inputs selected from the available pattern recognizor terms and external trigger input.

Branching conditions

Conditional and multiway branching on a logical combination of the branching inputs with IF/ELSE, CASE, WHILE and REPEAT constructs unconditional branching on completion of state actions using GOTO construction.

State actions

Start a named block of bus transactions (defined in bus transaction editor). Execute a named block of transactions with automatic retry after target disconnect/retry. Assert external trigger output (SNB).

Bus exerciser card

Transaction memory



Transactions are defined using address and data phases up to a maximum burst length of 1,750 data phases for a single transaction. Multiple transactions can be defined up to the maximum transaction memory depth of 13,950 phases.

Pattern recognizor

Up to seven logical combinations of signal patterns can be defined. Occurrences of these patterns are available to the test sequencer for triggering/branching. The pattern recognizor has access to the following signals:

- all PCI Bus signals
- internal state signals from the bus exerciser's master/target state machines
- protocol violation signal from protocol monitor When programmed to retry terminated transactions, five of the pattern terms are predefined.

Protocol monitor

The protocol monitor permanently monitors the bus control signals and checks 25 PCI protocol rules in real-time. A violation signal is available to the pattern recognizor and logic analyzer for triggering or branching. The data listers also check the traffic data captured by the logic analyzer against the same protocol rules and indicate which rule was violated.

Sideband signals

In addition to the PCI bus signals, the bus exerciser provides sideband signals which can be used to drive or monitor and trigger from other signals in the system under test.

Fixturing for in-system and stand-alone test

Adapters for in-system test



Adapt theHP E2910A for in-system testing at PCI slots

- HP E2911A for 5 V signalling environment
- HP E2913A for 3.3 V signalling environment

Adapters for stand-alone card test



Adapt the HP E2910A to support stand-alone (without PCI motherboard) testing of up to three PCI cards. The HP logic analyzer is still required to observe bus traffic.

- three PCI slots
- PCI arbiter
- mechanical housing
- connector for timing analysis with HP 16517/18A
- **HP E2912A** for 5 V signalling environment.
- **HP E2914A** for 3.3 V signalling environment

Configuration guide

Logic analyzer support

The HP 16500B logic analyzer system mainframe is integrated into the system via HP-IB and HP 16550A or 16554/5/6A logic analyzer cards are used to record bus/system activity for analysis. Up to 4k state data is uploaded to the PC for disassembly and analysis in the HP E2910A data listers (Timing data may also be analyzed). Standard PCI set-ups for the logic analyzer cards are included, and any modified set-ups can be transferred to and from the PC, or stored locally on the analyzer. You have full control over the logic analyzer via its local user interface, allowing you to use the logic analyzer trigger capabilities to filter and capture the bus activity you are interested in, for example:

- filtering out idle states
- capturing configuration transactions only
- capture acceses to a particular address range

System configuration

To use the HP E2910A PCI bus exerciser, the following additional equipment is required:

Computer

PC: IBM-PC or 100% compatible with recommended minimum 66MHz 486 CPU and 3.5" floppy drive.

Graphics: 640 x 480 VGA minimum. 1024 x 768 SVGA recommended.

O/S: MS-DOS version 5.0 with Windows 3.1 required.

Memory: 16 MB minimum, 24MB recommended.

Hard Disk: minimum 50MB available disk space required, 100MB recommended.

Expansion Slots: two ISA slots required for test sequencer card and HP-IB card.

I/O Interface: HP-IB interface card supplied with HP E2910A requires ISA slot in PC.

Logic analyzer: HP 16500B logic analyzer system mainframe with HP 16550A or HP 16554/5/6A logic analyzer card(s):Up to 4k of logic analyzer state data, or equivalentiming data, can be analyzed by the HP E2910A. 16554/5/6A memory depth must be set to 4k for upload into HP E2910A software.

	Number of LA Cards required:			
LA Card 16550A	32 Bit PCI 1	64 Bit PCI 2		
16554A 16555A 16556A	2	3		

Adapters

At least one of the following adapters is required to adapt the HP E2910A PCI bus exerciser for in-system or card test: HP E2911A: 5V in-system HP E2912A: 5V card HP E2913A: 3.3V in-system HP E2914A: 3.3V card

General specifications

Operating temperature range: +20°C to +30°C **Safety:** IEC1010, CSA1010

E2910A PCI bus exerciser:

- Product includes:
- software for MS-Windows 3.1
- PCI bus exerciser card
- test sequencer card (ISA) for PC
- power supply HP 15291A
- cables for logic analyzer
- HP-IB card and cable

HP 15291A power supply power requirements: 100-240V+/-10%, 50-60Hz, 300VA max.

Test sequencer card: requires 8-bit or 16-bit ISA slot. Occupies I/O-space only (DIP-Switch). No interrupts required.

Power consumption: 4 A max. @ +5V

Length: 175mm

HP E2910A P	CI specification	Reserved signals	Observable at separate connector to detect unexpected usage.
PCI Rev 2.1 speci to a particular ada product number: HP E2911A: 5 V HP E2912A: 5 V HP E2913A: 3.3	cifications use the outline of the ification. Specifications applicable apter are indicated by the adapter adapter for in-system test adapter for stand-alone card test V adapter for in-system test V adapter for stand-alone card test	3.1. Bus commands	Master: all command types, including "reserved", can be generated. Target: can be programmed to react on any set of command types. All read/write cycles are aliased to memory read/memory write commands.
2. Signal definition	All PCI bus signals (except JTAG), eight sideband signals (HP E2911A, E2913A only) and some internal state information can be observed by the logic analyzer and used by the pattern recognizor to change the test sequence in real time.	3.2.2. Addressing	Master: supports 32-bit addressing, configuration addressing (see 3.6.4) and 64 Bit addressing (dual address cycle). Target: can detect up to two independent 32 Bit address ranges ("01X" patterns on AD[31::0]) or IDSEL and qualify with any set of command types C/BE[3::0]. Can detect one 64 Bit address range (01x pattern, see 3.9.1).
2.2.6. Interrupts pins (optional)	Any of the four interrupts can be asserted at any time.		
2.2.7. Cache support pins (optional)	Not implemented/supported. HP E2912A, HP E2914A: SBO# and SDONE pulled up.	3.2.3. Byte alignment 3.3 Bus transactions	Master: any combination of AD[1::0] and C/BE[3::0] can be programmed.
2.2.8 Additional signals	PRSNT# Pins: see section 4.4.1 CLKRUN#: Not supported since not defined for connector.		Target: always returns all data bytes. Any command can be programmed as burst or single transfer. 0 to 30 wait states can be generated in any master or target data phase. More waits can be inserted using data_step commands. Completion: the length of a burst is programmable. Time-out: master terminates as part of the intended test, not as a
2.2.9. 64-bit bus extension pins (optional)	Master and target support 64-bit data transfers. A second HP 16550A required analyzer card to observe 64 Bit signals.		
2.2.9. JTAG/boundary scan pins (optional)	Not supported. HP E2911A, HP E2913A: TDI is hardwired to TDO. HP E2912A, HP E2914A: not connected.	3.3.3.1. Master initiated termination	
2.3. Sideband signals	HP E2911A, HP E2913A: eight input/output sideband signals are observable at the logic analyzer (2nd HP 16550A card required) and pattern recognizor to influence the test sequence. four open-drain and four totem- pole sideband outputs can be programmed on a single clock cycle basis as part of the intended		reaction to the deassertion of GNT#. Master abort: six cycles after FRAME# is asserted, if target does not respond.

test. HP E2912A, HP E2914A: no sideband signals.

3.3.3.2. Target initiated termination	Master: can be programmed to retry a target-terminated access, starting at the address of the next untransferred data. Target: terminations can be programmed in any target data phase. The assertion of STOP# can be placed on a clock cycle basis using the "wait" parameter. Disconnect A/B: terminates after	 3.6. Exclusive access 3.6.1 Starting an exclusive access 	Master: can start a locked access and complete it at the end of the next transaction or later. Target: locks its whole address range. Master: releases LOCK# after master or target abort.
	data transfer. Retry/disconnect C: terminates without data transfer. Target abort: terminates without data transfer and deasserts DEVSEL#.	3.6.3 Accessing a locked agent	Master: withholds a locked access while another master has LOCK# asserted. Target: signals retry when locked and accessed with a non-exclusive access.
3.4. Arbitration	Master: can request the bus independent of or in combination with transactions. HP E2912A, HP E2914A: contain	3.6.4 Completing an exclusive access	Master: LOCK# is released one clock cycle after the last data in a burst.
	arbiter with fixed priorities for slot 1 (highest), HP E2910A, slot 2, slot 3 (lowest). This provides a more	3.6.6. Complete bus lock	HP E2912A, HP E2914A: not supported
	predictable test environment than a fairness-based algorithm.	3.7.1. Device	Target: can detect up to two independent 32 Bit address ranges ("01X" patterns on AD[31::0]) or IDSEL and qualify it with any set of commands types C/BE[3::0]. Can detect one 64 Bit address range (01x pattern, see 3.9.1).
3.4.2. Fast back-to-back transactions	Master: fast back-to-back can be selected as part of intended test. Target: supports fast back-to-back.	selection	
3.4.3. Arbitration parking	HP E2912A, HP E2914A: the central arbiter uses HP E2910A as a parking master which drives AD[63::0] and C/BE[7::0], PAR and PAR64 to a stable value.	3.7.2. Special cycle	Master: can initiate a special cycle with programmable message. Bursted special cycle is not supported.
3.5 Latency on PCI	Arbitration latency: 1 clock cycle fixed (HP E2912A , HP E2914A , see 3.4). Bus acquisition latency: one or more clock cycles programmable. Data transfer latency (waits): For both master and target any number of wait cycles between 0	3.7.3. Address/data stepping	Any number of discrete steps, with programmable values for AD[63::0], C/BE[7::0], PAR, and PAR64 for each step, can be inserted in the address phase (master only) or data phase (master or target). Continuous stepping is not implemented.
	and 30 can be programmable individually per data phase. Additional waits can be inserted using data_step commands. Master latency timer: none, see 3.3.3.1.	3.7.4. (Accepting) configuration cycles	Target: can react on IDSEL qualified by any set of command types and present any data (see 6).

3.7.4.1. Generating configuration cycles 3.7.5. Interrupt acknowledge	Master can generate all types of configuration cycle (HP E2911A: only if the motherboard connects IDSELx to address lines). Master: can generate an interrupt acknowledge cycle. Target: can respond to an interrupt acknowledge cycle as part of the intended test.	4.2.1. 5V signaling environment	The following adapters supported the 5 V signalling environment: HP E2911A: 5 V adapter for in- system test. HP E2912A: 5 V adapter for stand-alone card test. HP E2911A, HP E2912A: data outputs are driven by 74FCT16823ET registered buffers, and sensed by 74ABT16245 buffers. Control	
3.8.1. Parity	Address or data phases can individually be programmed to generate correct or wrong PAR/ PAR64 bits.	a phases can outputs are driven by 74AB programmed to incident wave switching bu sensed by 74FCT16245ET I HP E2912A: 3.3V is supp		
3.8.2.1 PERR#	Master and target can assert PERR# 2 clock cycles after any read/write data transfer as part of the intended test. Although parity errors can be detected they are not used to assert PERR#.		the 3.3V power pins, allowing 5 V signalling cards which have some devices powered from 3.3 V to be tested. HP E2911A: all buffers are powered from the PCI connector.	
3.8.2.2 SERR#	Master and target can assert SERR# at any time as part of the intended test.	4.2.2. 3.3V signaling environment	The following adapters support the 3.3 V signalling environment: HP E2913A: 3.3 V adapter for in-	
3.9. Cache support	Not implemented/supported.		system test. HP E2914A: 3.3 V adapter for stand-alone card test.	
3.10. 64-Bit bus extension	Master: can initiate 64-bit data transfers. Target: each transaction can individually accept or refuse 64-bit data accesses as part of the intended test.		HP E2913A, HP E2914A: data outputs are driven by 74LVT16952 registered buffers, and sensed by 74LVT16245 buffers. Control outputs are driven by 74LVT244 buffers (selected as incident wave switching devices), and sensed by	
3.10.1. 64-bit addressing on PCI	Master: can initiate a dual address cycle. Optionally AD[63::32] and C/BE[7::4] can be driven as well Target: can decode one 64-bit address (01x pattern). HI-ADDR and command are decoded from AD[31::0], C/BE[3::0].	4.2.3.1. Clock specification	74LVT16245 buffers. HP E2913A: all buffers are powered from the PCI connector. Operates at any frequency between DC and 33 MHz. The frequency must be known to be in one of the ranges: <5 MHz, 5 - 20 MHz, or >20 MHz. In the two highest ranges the frequency must be stable. The range < 5 MHz is intended for very slow devices such as ASIC emulators and expects a large hold-time. HP E2911A, HP E2913A: clocked from the PCI connector, HD E2019A	

HP E2911A, HP E2913A: clocked from the PCI connector. HP E2912A, E2914A: each slot can be clocked from internal oscillator (33.3 MHz or 16.6 MHz) or from one of two BNC-type external clock inputs.

4.2.3.2.	CLOCK FREQUENCY > 5 MHz				4.4 Expansion	Section 4.4 applies to
Timing parameters	Symbol tva (data)l	Min 2 ns	Max 18 ns	Notes 1, 6	board specification	in-system adapters HP E2911A and HP E2913A only
Above 5 MHz	tval (control) tval (PAR) tval (ptp) ton	2 ns 2 ns 2 ns 2 ns 2 ns	18 ns 20 ns 18 ns	2, 5, 6 3, 5, 6 4, 5, 6	4.4.1. Board pin assignment	PRSNTx# signals are programmable.
	toff tsu tsu (ptp) th Notes:	7 ns 10 ns 0 ns	28 ns		4.4.2 Power requirements	HP E2911A: consumes 0.5A @ 5V from PCI slot for I/O buffers HP 2913A: consumes 0.5A @ 3.3V from PCI slot for I/O buffers.
	All transitions measured at 1.5 V. 1. AD[63::0], C/BE#[7::0], SERR#, PERR#, INTA-D#			E RR #,	4.4.3.1. Trace length limits	All PCI signal traces are max. 1.5 inches (32-bit), 2 inches (64-bit). CLK signal trace is 2.5 inches.
	2. FRAME#, DEVSEL#, IDSEL, TRDY#, IRDY#, LOCK#, STOP#, REQ64#, ACK64#				4.4.3.3. Impedance	80 Ohm typical.
	 3. PAR, PAR64 4. GNT#, REQ# 5. Driven by incident wave switching drivers (HP E2911/12A: 74ABT25245, HP E2913/14A: selected 74LVT244) 6. Exceeds limit set by PCI Spec. Rev 2.1 			1A:	4.4.3.4. Signal loading	HP E2911A: AD[63::0] and C/BE[7::0] 14 pF typical. Control signals 20 pF typical. HP E2913A: AD[63::0] and C/BE[7::0] 18 pF typical. Control signals 20 pF typical. All signals are connected to one input buffer and one output buffer
Below 5 MHz			4.4 D	on opposite sides of the PC board.		
	Symbol tval tsu th	Min 0 ns 40 ns	Max 60 ns		4.4.x Reset	RST# tristates all output buffers and resets all bus statemachines on HP E2910A board.
4.3 System (motherboard) specification	Section 4.3 applies to add-in rd) card adapters HP E2912A and		5.2 Expansion card physical dimensions	Length: like a long card. Close to the PCI connector shorter than a short card (160 mm). Height: 265 mm including		
4.3.1 Clock skew (motherboard)	2 ns max.					HP E2910A and cables to logic analyzer. Connector bevel: 20 degrees.
4.3.2. Reset	RST# is under SW control.		5.2.1 Connector	HP E2911A: 5 V 64-bit card edge connector.		
4.3.4.1. Power requirements	HP E2912 5V/3.3V, 1.5 -12V for 3 F HP E2914 3.3V/5V, 1.5 -12V for 3 F	5A @ +1 PCI slots A: provi 5A @ +1	2V, and (s togethe ides 6A @ 2V, and ().5A @ er. @).5A @	physical description	 HP E2913A: universal 64-bit card edge connector. HP E2912A: 5 V 64-bit connector. HP E2914A: 3.3V/64-bit connector.
4.3.6.2 Motherboard impedance	45 Ohm typ	oical.				
4.3.7 Connector pin assignment	PRSNTx# s can be obs connector.	erved at				

6. Configuration space	HP E2910A does not interactively participate in the configuration phase. However, the intended test can be programmed to emulate any device's configuration space, (e.g. device with multiple memory spaces, bus bridge, multi-function device.) by presenting a set of answers to expected queries. Even strange, inconsistent or wrong data can be programmed to stress the BIOS.

7. 66 MHz PCI Not supported.



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